S	Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/052,870	SHI ET AL.	
Examiner	Art Unit	
Jason M. Perilla	2611	

	SEAR	CHED	
Class	Subclass	Date	Examiner
375	219	9/1/2006	JP
	316	9/1/2006	JP
	324	9/1/2006	JP
	344	9/1/2006	JP
	345	9/1/2006	JP
	346	9/1/2006	JP
455	130	9/1/2006	JP
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INTERFERENCE SEARCHED		
Subclass	Date	Examiner
316	9/1/2006	JP
324	9/1/2006	JP
	Subclass 316	Subclass Date 316 9/1/2006

SEARCH (INCLUDING SEAR		7)
	DATE	EXMR
East USPAT USPGPUB EPO JPO	9/1/2006	JP
Inventor Name Search EAST/EDAN	9/1/2006	JP
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